

CSIR - CENTRAL ELECTROCHEMICAL RESEARCH INSTITUTE
KARAIKUDI – 630 003

REQUISITION FORM FOR XPS / DEPTH PROFILE / UPS / ISS / REELS ANALYSIS

1. **Name of the User (Mr. / Ms. / Dr.)** :
Designation & Dept./Division

2. **Institution / Industry Name and Address:**

3. **Email ID** :

4. **Phone No. / Mobile No.** :

5. **Purpose** : UG/PG/M.Phil Project Work / Ph.D Work / Research
Others (Please mention):

6. **Number of Samples** :
(If more than 2 samples, use new requisition form)

SAMPLE INFORMATION

7. **Sample (1) Name** :

- i. Physical Nature : Powder Pellet Film
- ii. Chemical Nature : Organic Inorganic Organic - Inorganic Carbon-based
- iii. Sample Property : Conducting Semiconducting Insulating

- iv. Possible Elements :
(Even in Low concentration)
- v. Elements for High resolution scan :

8. **Sample (2) Name** :

- i. Physical Nature : Powder Pellet Film
- ii. Chemical Nature : Organic Inorganic Organic - Inorganic Carbon-based
- iii. Sample Property : Conducting Semiconducting Insulating

- iv. Possible Elements :
(Even in Low concentration)
- v. Elements for High resolution scan :

9. **Surface cleaning required** (Not applicable for powder samples) : Yes / No

10. **Relevant literature reference if any, please attach** :

11. **Remarks/special analysis request if any** :

Certified that the request is for academic / above mentioned purpose. Concessional charges may kindly be collected. Further certified that we will under take guarantee for the payment of concessional charges.

Signature of the User
Date:

Signature of the Guide
Seal

Signature of the HoD / Principal
Seal

Sample Requirement:

- ❖ Solid samples like powder (5-10 mg), Pellet (1 cm dia with 2-3 mm thickness), thin film sample area(1 cm²) may be supplied.
- ❖ The sample should not contain any volatile/degassing materials which will affect Ultra High vacuum in the analysis chamber(No out gassing allowed). The samples may be preconditioned in Vacuum oven.
- ❖ Powders may be made into pellet or form a thin coating on a clean conducting substrate like silicon, aluminium or copper foil, if necessary.
- ❖ User should clearly mention if the sample needs etching(surface cleaning). It may be noted that the etching may alter the chemical composition and chemical state to some extent.
- ❖ Sample containing high vapour pressure elements such as **Na, K, S, P,F, Zn, Se, As, I, Te or Hg** are not suitable for depth profile analysis.
- ❖ UPS is possible only on sufficiently conducting samples.

Charge per sample / per mode:

Description	Academic Institution / CSIR Labs [Concessional]	R&D Labs	Industry
XPS	₹ 4600 + 18% GST	₹ 9200 + 18% GST	₹ 18400 + 18% GST
DEPTH PROFILE# (1 Hour / per sample)	₹ 4600 + 18% GST	₹ 9200 + 18% GST	₹ 18400 + 18% GST
UPS	₹ 4600 + 18% GST	₹ 9200 + 18% GST	₹ 18400 + 18% GST
ISS	₹ 4600 + 18% GST	₹ 9200 + 18% GST	₹ 18400 + 18% GST
REELS	₹ 4600 + 18% GST	₹ 9200 + 18% GST	₹ 18400 + 18% GST

For Depth profile, samples requiring more than one hour of analysis, extra charge will be collected.